

<b>Notice of References Cited</b>	Application/Control No. 10/781,115	Applicant(s)/Patent Under Reexamination CRANDALL ET AL.	
	Examiner Anthony Weier	Art Unit 1761	Page 1 of 1

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	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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